PATENT ABSTRACTS OF JAPAN

(11)Publication number:

2003-315286

(43) Date of publication of application: 06.11.2003

(51)Int.Cl.

G01N 23/04

(21)Application number: 2002-122464

(71)Applicant: YAMATO SCALE CO LTD

(22) Date of filing:

24.04.2002

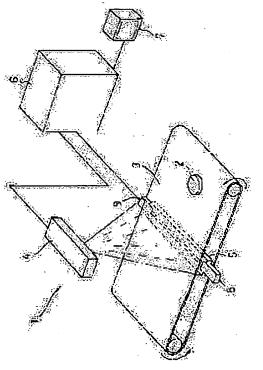
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(54) X-RAY FOREIGN-MATTER DETECTOR

(57)Abstract:

PROBLEM TO BE SOLVED: To provide an X-ray foreign-matter detector that can be checked always for whether or not it functions normally, without stopping a production line.

SOLUTION: This X-ray foreign-matter detector 1 is provided with a conveyor 3 for transporting an object 2 to be inspected, an X-ray generator 4 for projecting X-rays upon the object 2 transported on the conveyor 3, and an X-ray sensor 5 for detecting the transmittance of the X-rays projected upon the object 2 from the generator 4. Test pieces 8 and 9 for confirming sensitivity of this detector 1 are positioned at least one end section of the sensor 5 or the projected position of the X-rays where the object 2 is not passed in the vicinity of at least end section of the sensor 5.



LEGAL STATUS

[Date of request for examination]

04.04.2005

[Date of sending the examiner's decision of rejection]

Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]